

09/248, 465

L Number	Hits	Search Text	DB	Time stamp
5	453	tak\$2 near3 (test\$3 exam\$4) same (on-line internet www world adj wide adj web)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:43
6	14	((tak\$2 near3 (test\$3 exam\$4) same (on-line internet www world adj wide adj web)) same (paying or paid tuition cost price))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:34
7	0	(internet on-line www world adj wide adj web) same (test-making test adj maker\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:39
8	3	(internet on-line www world adj wide adj web) and (test-making test adj maker\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:39
9	119350	(access\$3) with (database\$1 or member\$5 or network)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:42
10	34461	((access\$3) with (database\$1 or member\$5 or network)) and (paying or paid tuition cost)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:44
11	3862	((access\$3) with (database\$1 or member\$5 or network)) same (paying or paid tuition cost)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:44
12	709	((access\$3) with (database\$1 or member\$5 or network)) same (paying or paid tuition cost)) same (on-line internet www)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:45
13	0	((access\$3) with (database\$1 or member\$5 or network)) same (paying or paid tuition cost)) same (on-line internet www)) same (test-making test adj maker\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:46
14	0	((access\$3) with (database\$1 or member\$5 or network)) same (paying or paid tuition cost)) same (on-line internet www)) and (test-making test adj maker\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:46
15	22	((access\$3) with (database\$1 or member\$5 or network)) same (paying or paid tuition cost)) same (on-line internet www)) same revenue\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/09 16:47

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	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L3	242	tak\$4 near3 (test\$3 exam\$3) same (on-line internet www world adj wide adj web)	USPAT	2002/07/23 10:49
2	BRS	L4	4	3 same (paying or paid tuition cost price)	USPAT	2002/07/23 10:18
3	BRS	L6	80179	(access\$5) with (database\$1 or member\$5 network)	USPAT	2002/07/23 10:21
4	BRS	L7	494	((internet on-line www or world adj wide adj web) same (test-making test maker\$1)) and ((access\$5) with (database\$1 or member\$5 network)) and (pay\$5 or cost\$3 paid or fee\$3 or tuition)	USPAT	2002/07/23 10:25
5	BRS	L8	77	((internet on-line www or world adj wide adj web) same (test-making test maker\$1)) and ((access\$5) with (database\$1 or member\$5 network)) same (pay\$5 or cost\$3 paid or fee\$3 or tuiti	USPAT	2002/07/23 10:27
6	BRS	L5	109	3 and (paying or paid tuition cost price)	USPAT	2002/07/23 10:49
7	BRS	L9	29	tak\$4 near3 (test\$3 exam\$3) same (on-line internet www world adj wide adj web)	EPO; JPO; DERWE NT; IBM_T DB	2002/07/23 10:50
8	BRS	L14	5	tak\$4 near3 (test\$3 exam\$3) same (on-line internet www world adj wide adj web) and (pay\$5 or paid or fee\$3 or tuition or price or charg\$3 or	EPO; JPO; DERWE NT; IBM_T DB	2002/07/23 10:51

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